

Specification of Automotive MLCC (Reference sheet)

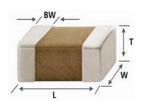


● Supplier : Samsung Electro-Mechanics ● Samsung P/N : CL10B105K08VPNC

● AEC-Q200 Qualified

A. Dimension

Dimension



Size	0603 inch
L	1.60±0.10 mm
W	0.80±0.10 mm
Т	0.80±0.10 mm
BW	0.30±0.20 mm

B. Samsung Part Number

<u>CL</u>	<u>10</u>	<u>B</u>	<u>105</u>	<u>K</u>	<u>0</u>	<u>8</u>	<u>v</u>	<u>P</u>	<u>N</u>	<u>C</u>
1	2	3	4	(5)	6	①	8	9	10	11

① Series	Samsung Multi-layer Ceramic Capacitor		
② Size	0603 (inch code)	L: 1.60±0.10 mm	W :0.80±0.10 mm
3 Dielectric	X7R	8 Inner electrode	Ni
④ Capacitance	1 <i>μ</i> F	Termination	Metal-Epoxy
⑤ Capacitance	± 10%	Plating	Sn 100% (Pb Free)
tolerance		Product	Automotive
Rated Voltage	16 V	Special code	Normal
① Thickness	0.80±0.10 mm	1 Packaging	Cardboard Type, 7" Reel

C. Reliability Test and Judgement condition

Test items	Performance	Test condition
High Temperature	Appearance : No abnormal exterior appearance	Unpowered, 1,000hrs @ Max. temperature
Exposure	Capacitance Change Within ±10 %	Measurement at 24±2hrs after test conclusion
	Tan δ :0.125 max.	
	IR :More than 10,000 MΩ or 500 MΩ×μF	Initial Measurement 2*
	Whichever is smaller	Final Measurement 3*
Temperature Cycling	Appearance : No abnormal exterior appearance	1,000Cycles
	Capacitance Change Within ±10 %	Initial Measurement 2*
	Tan δ :0.125 max.	Final Measurement 3*
	IR : More than 10,000 № or 500 №×μF	Measurement at 24±2hrs after test conclusion
	Whichever is smaller	1 cycle condition : -55+0/-3°C(30±3min) → Room Temp. (1min)
		→ 125+3/-0°C(30±3min) → Room Temp. (1min)
Destructive Physical	No Defects or abnormalities	Per EIA 469
Analysis		
Humidity Bias	Appearance : No abnormal exterior appearance	1,000hrs 85 ℃/85%RH, Rated Voltage and 1.3~1.5V,
	Capacitance Change Within ±12.5 %	Add 100kohm resistor
	Tan δ :0.125 max.	Initial Measurement 2*
	IR :More than 500 MΩ or 25 MΩ×μF	Final Measurement 4*
	Whichever is smaller	Measurement at 24±2hrs after test conclusion
		The charge/discharge current is less than 50mA.
High Temperature	Appearance : No abnormal exterior appearance	1,000hrs @ 125℃, 150% Rated Voltage,
Operating Life	Capacitance Change Within ±12.5 %	Initial Measurement 2*
	Tan δ :0.125 max.	Final Measurement 4*
	IR :More than 1,000 ^M Ω or 50 ^M Ω×μF	Measurement at 24±2hrs after test conclusion
	Whichever is smaller	The charge/discharge current is less than 50mA.
	4	

	Performance	Test condition					
External Visual	No abnormal exterior appearance	Microscope ('10)					
Physical Dimension Within the specified dimensions		Using The	e caliper	'S			
Mechanical Shock	Appearance : No abnormal exterior appearance	Three shocks in each direction should be applied along					
	Capacitance Change Within ±10 %	3 mutually perpendicular axes of the test specimen (18 shocks)					
	Tan δ, IR : Initial spec.	Peak value Duration Wave Ve				Velocity	
		1,5	500G	0.5ms	Half sine	4.7m/sec	
		Initial Measurement 2*					
		Final Measurement 5*					
Vibration	Appearance : No abnormal exterior appearance	5g's for 2	0min., 1	2cycles ead	ch of 3 orie	ntations,	
	Capacitance Change Within ±10 %	Use 8"×5	" PCB 0	.031" Thick	7 secure p	oints on one lo	ong side
	Tan δ, IR : Initial spec.	and 2 sec	cure poir	nts at corne	rs of oppos	site sides. Part	s mounted
		within 2" 1	from any	secure po	int. Test fro	om 10~2,000Hz	
		Initial Me	asureme	ent 2*			
		Final Mea	asureme	nt 5*			
Resistance to	Appearance : No abnormal exterior appearance	preheatin	ng : 150°0	C for 60~12	0 sec.		
Solder Heat	Capacitance Change Within ±10 %	Solder po	ot: 260±	5℃, 10±1s	ec.		
	Tan δ, IR : Initial spec.	Initial Me	asureme	ent 2*			
		Final Measurement 3*					
ESD	Appearance : No abnormal exterior appearance	AEC-Q20	00-002 o	r ISO/DIS1	0605		
	Capacitance Change Within ±10 %	Initial Measurement 2*					
	Tan δ, IR : Initial spec.	Final Measurement 4*					
Solderability	95% of the terminations is to be soldered	a) Preheat at 155 °C for 4 hours, Immerse in solder for 5s at 245±5 °C					
	evenly and continuously	b) Steam aging for 8 hours, Immerse in solder for 5s at 245±5 $^{\circ}\mathrm{C}$					
		c) Steam aging for 8 hours, Immerse in solder for 120s at 260±5 °C					
		solder : a solution ethanol and rosin					
Electrical	Capacitance : Within specified tolerance	*A capacitor prior to measuring the capacitance is heat treated at					
Characterization	Tan δ:0.1 max.	150 +0/-10 ℃ for 1hour and maintained in ambient air for 24±2 hou					for 24±2 hours
	IR(25°C): More than 10,000 № or 500 №×μF	The Capacitance / D.F. should be measured at 25 °C,					
	Whichever is smaller	1 kHz ± 10%, 1 ± 0.2 Vrms					
	IR(125 °C) More than 1,000 MΩ or 10 MΩ×μF	I.R. should be measured with a DC voltage not exceeding					ding
	Whichever is smaller	Rated Voltage @25℃, @125℃ for 60~120 sec.					
	B: 1 1: 01	D. 1 1.	01 11	0500/			
	Dielectric Strength					oltage for 1~5	seconds
Board Flex	Appearance : No abnormal exterior appearance	•		nit, 3 mm fo	i ou secono	uo I	
	Capacitance Change Within ±10 %	Initial Measurement 2*					
T	Appearance : No abnormal exterior appearance	Final Measurement 5* 10 N, for 60 sec.					
Terminal	Capacitance Change Within ±10 %			ent 2*			
Strength(SMD)	Capacitance Change Within 110 /0	Initial Measurement 2* Final Measurement 5*					
Beem Les d	Destruction value should be exceed 20 N	Beam speed: 0.5±0.05 mm/sec					
Beam Load	X7R	beam spe	ccu .	U.U±U.UU IIII	·/ 3CC		
Temperature	From -55 °C to 125 °C, Capacitance change shou	he withir	n +15%				
Characteristics	1 Tom -35 0 to 125 0, Capacitance change shou	DC MITHI	11 11 10 /0				

D. Recommended Soldering method :

Reflow (Reflow Peak Temperature : 260 +0/-5°C, 30sec.), Meet IPC/JEDEC J-STD-020 D Standard

- *1 : The figure indicates typical specification. Please refer to individual specifications.
- *2 : Initial measurement : Perform a heat treatment at 150 +0/-10 $^{\circ}\mathrm{C}$ for one hour after soldering process. and then let sit for 24±2 hours at room temperature. Perform the initial measurement.
- $^{\star}3$: Final measurement : Let sit for 24 \pm 2 hours at room temperature after test conclusion, then measure.
- *4 : Final measurement : Perform a heat treatment at 150 +0/-10 °C for one hour after soldering process. and then let sit for 24±2 hours at room temperature. Perform the initial measurement.
- *5 : Final measurement : Let measure within 24 hours at room temperature after test conclusion.



Product specifications included in the specifications are effective as of March 1, 2013.

Please be advised that they are standard product specifications for reference only.

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- ② Medical equipment
- 3 Military equipment
- 4 Disaster prevention/crime prevention equipment
- ⑤ Power plant control equipment
- 6 Atomic energy-related equipment
- ① Undersea equipment
- 8 Traffic signal equipment
- Data-processing equipment
- @ Electric heating apparatus, burning equipment
- Safety equipment
- @ Any other applications with the same as or similar complexity or reliability to the applications